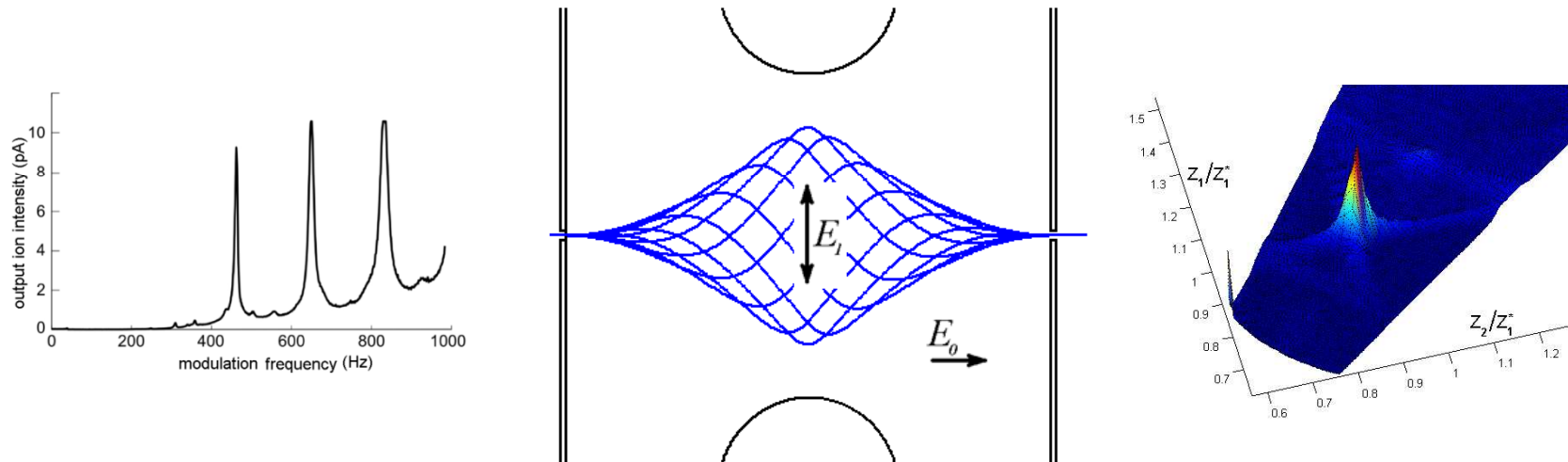


Transversal Modulation IMS. (TM-IMS)

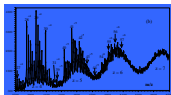
“Path to next-generation IMS: new concepts, advanced instrumentation, and leveraging the ion-molecule chemistry”



Guillermo Vidal-de-Miguel^{1,2}, Myriam Macia¹, Jaime Cuevas¹ & Cesar Barrios¹.

¹ SEADM S.L.

² Valladolid University, Energy and Fluid Mechanics Engineering Dep.



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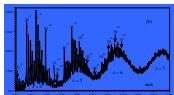
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Summary

- Principle of operation:
 - One stage.
 - Higher resonances and curtain gas.
 - Two stages.
- Demonstrator TMIMS-1:
 - Architecture.
 - Resolving power.
 - Robustness
- Demonstrator TMIMS-2:
 - Architecture.
 - Background reduction.
 - IMS-IMS analysis.
- Numerical simulations.
- Conclusions.



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Principle of operation: One stage.

- Ideal uniform electric fields:

- Velocity \rightarrow trajectories:

$$u = KE_0 \quad x = KE_0(t - t_0)$$

$$v = KE_1 \sin(\Omega t) \quad y = 2 \frac{KE_1}{\Omega} \sin\left(\frac{\Omega}{2}(t - t_0)\right) \sin\left(\frac{\Omega}{2}(t + t_0)\right)$$

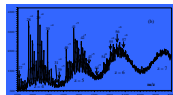
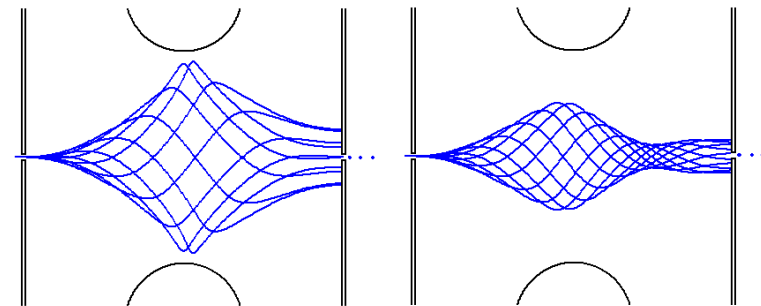
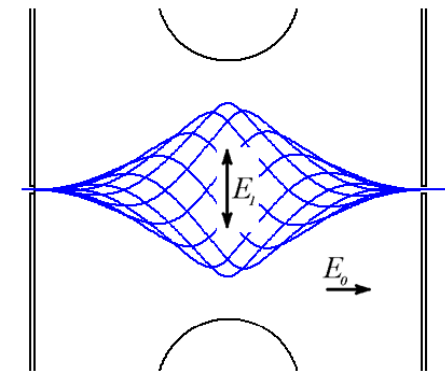
- Distance to the outlet slit

$$Y = 2 \frac{KE_1}{\Omega} \sin\left(\frac{\Omega l}{2KE_0}\right) \sin\left(\Omega t - \frac{\Omega l}{2KE_0}\right)$$

= 0

- Selection criterion:

$$K = \frac{\Omega l}{2\pi E_0}$$



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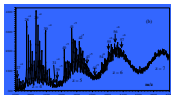
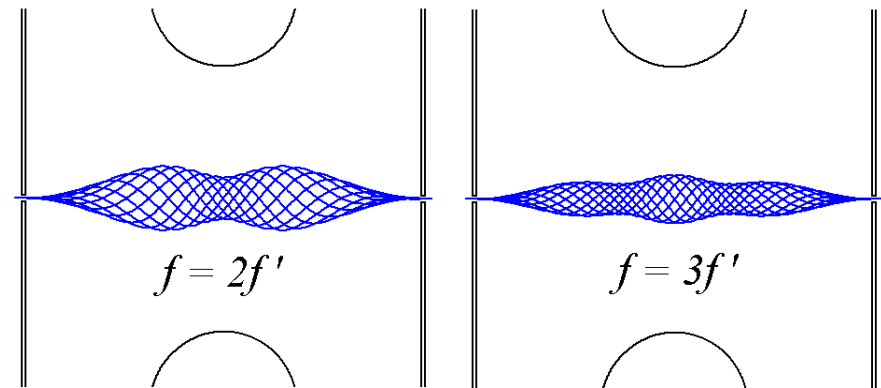
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Principle of operation: Higher resonances.

- Resonant mobilities:

$$K_n = \frac{\Omega l}{2n\pi E_0}$$

- Curtain gas in the inlet slit acts as high mobility pass filter:
 - sweeps away low mobility ions and prevents agglomeration of resonant peaks.
- Resolving power of the high pass filter $R > 2$ is enough to separate K_1 and $K_2 = K_1/2$.



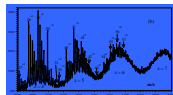
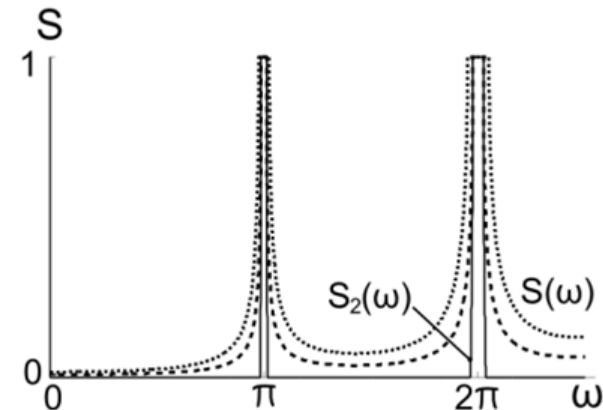
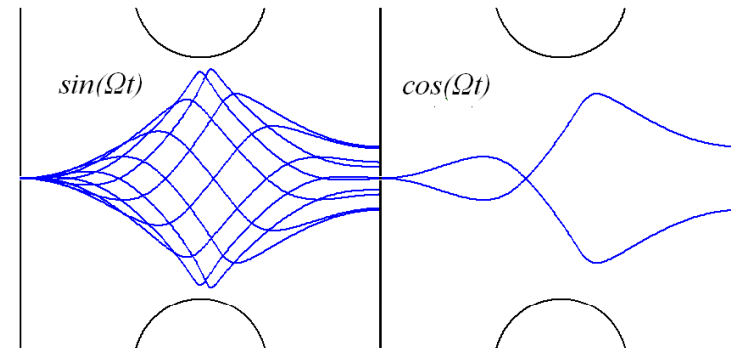
Principle of operation: Two stages.

- One stage produces a pulsed output of non desired ions:

$$Y = 2 \frac{KE_1}{\Omega} \sin\left(\frac{\Omega l}{2KE_0}\right) \sin\left(\Omega t - \frac{\Omega l}{2KE_0}\right)$$

(The second sine term is circled in red with an arrow pointing to = 0)

- Two stages operated in quadrature (same frequency) eliminate the pulsed output.
- Each stage can be operated with a different gas and a different voltage
 - *IMS-IMS analysis.*



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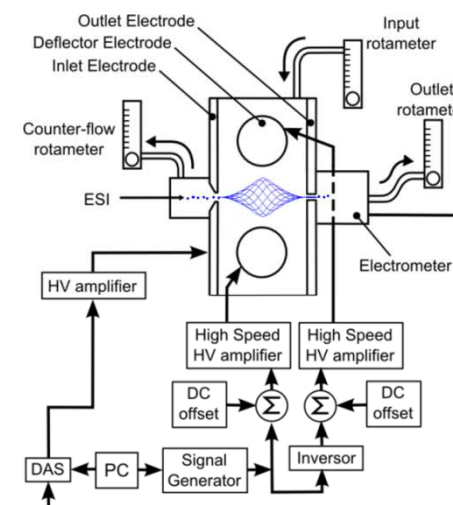
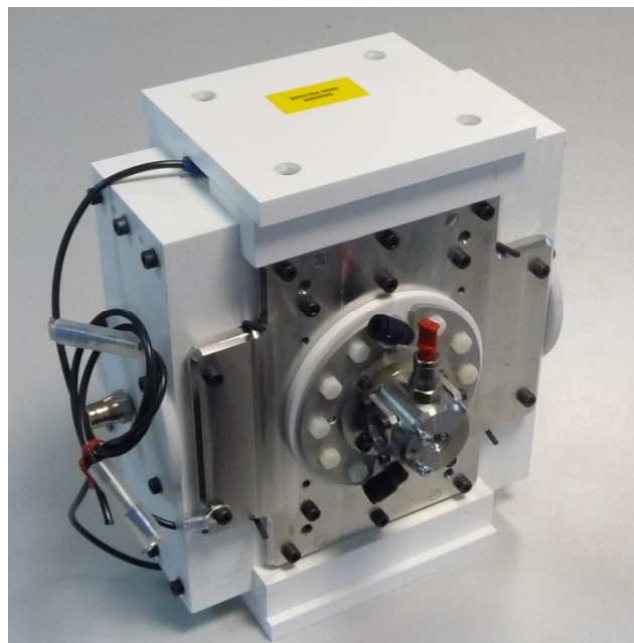
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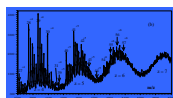
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TMIMS-1: Architecture.

- One single stage.
- Nano-ESI ion source
- Electrometer detector
- IMS analysis



Anal. Chem., 2012, 84 (18), pp 7831–7837



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TMIMS-1: Resolving power (*Res*).

Theoretical estimation

- Ions spread due to diffusion.

$$\sigma_r^2 = 2D\tau$$

- Calculate instantaneous signal $N(Y, \sigma_r)$

$$S = \frac{1}{\sqrt{2\pi}\sigma_r} e^{-\frac{\left(\frac{E_1}{E_0} \frac{K-K_0}{K_0} \sin(\Omega t)\right)^2}{2\sigma_k^2}}$$

- Integrated averaged signal.

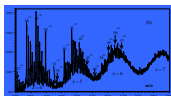
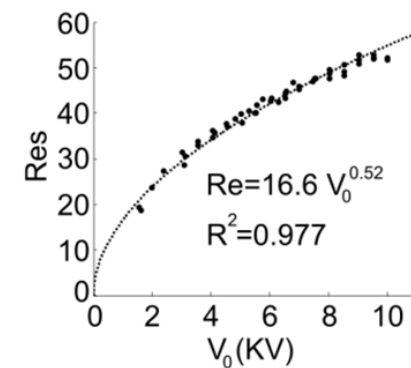
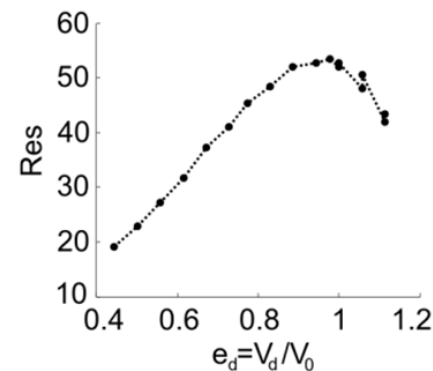
$$\bar{S} = \int_0^{2\pi} e^{-\frac{1}{2}\left(\frac{K}{K_0}-1\right)^2 A \cdot \sin^2(\theta)} d\theta$$

- Reconstruct spectrum, FWHH.

$$R_D \approx 0.187 \frac{E_1}{E_0} \sqrt{\frac{V_0 e}{k_B T}}$$

Experimental results

- Res* grows with the square root of the axial voltage.
- Res* grows with the deflector voltage until trajectories collide with deflector electrodes.



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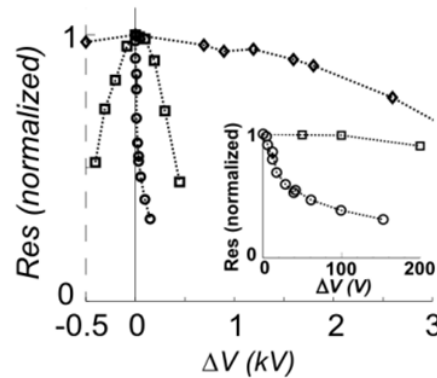
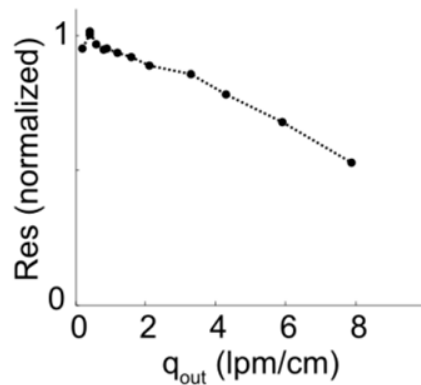
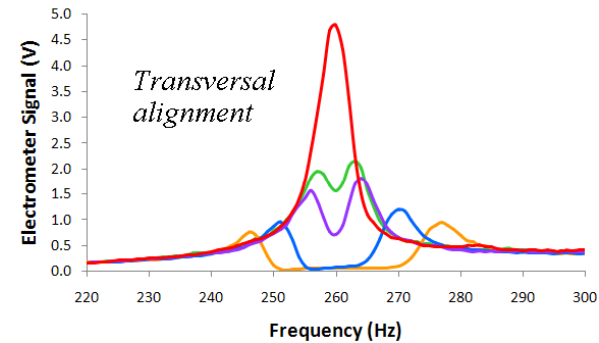
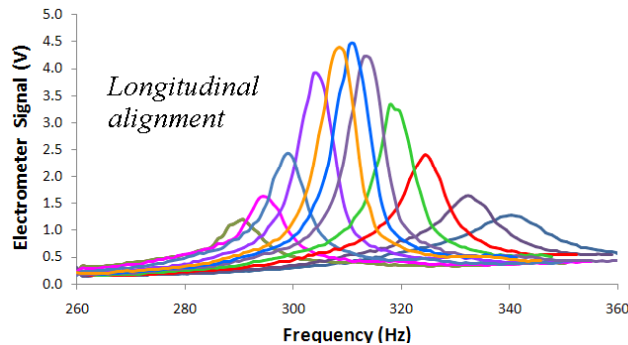
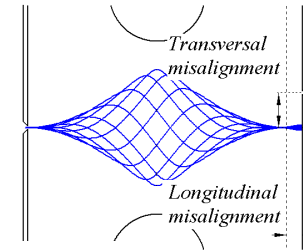
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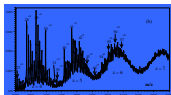
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TMIMS-1: Robustness.

- Electronic alignment compensates for mechanical misalignments.
 - Tolerates mechanical misalignments as high as 1mm.
 - Tolerates 5V error in mean deflector voltage.



- Transversal voltage: circles
- Longitudinal voltage: squares
- Different wave amplitude voltages: diamonds



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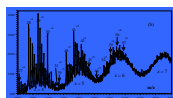
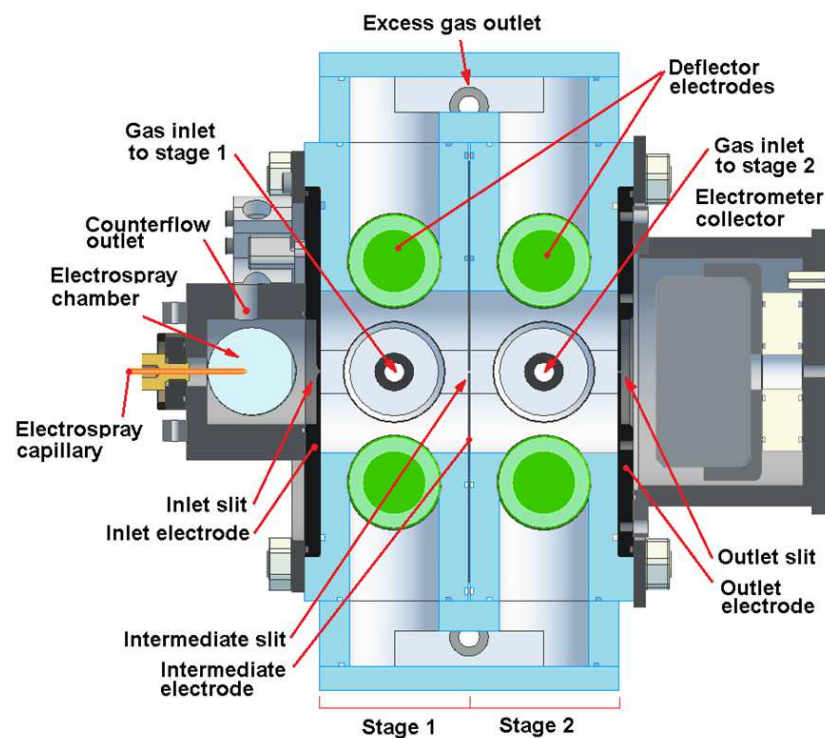


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TMIMS-2: Architecture.

- Two stages.
- Two gases.
- Nano-ESI ion source
- Electrometer detector
- IMS and IMS² analysis



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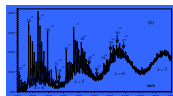
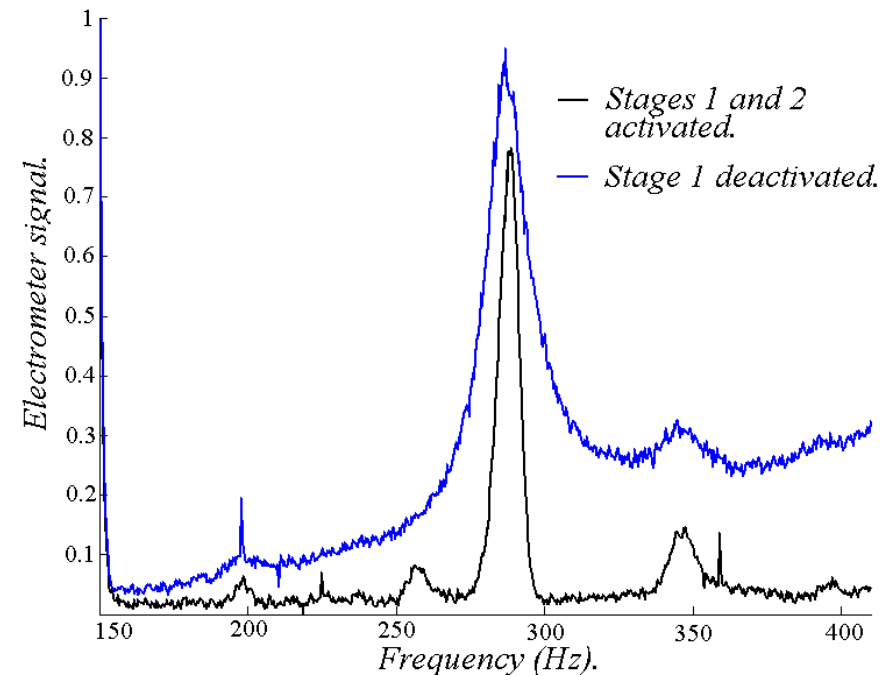
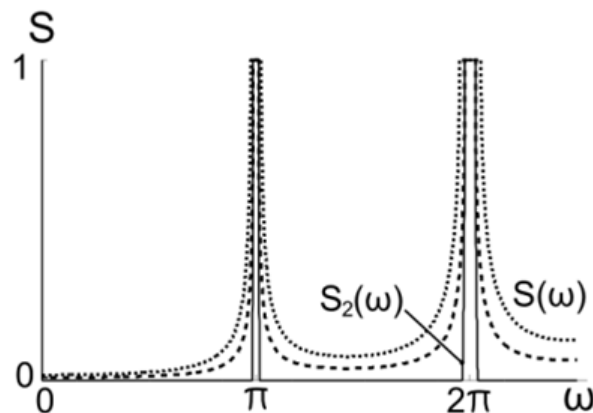
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TMIMS-2: Background reduction.

- Synchronization of Stages eliminates pulsed signals



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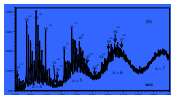
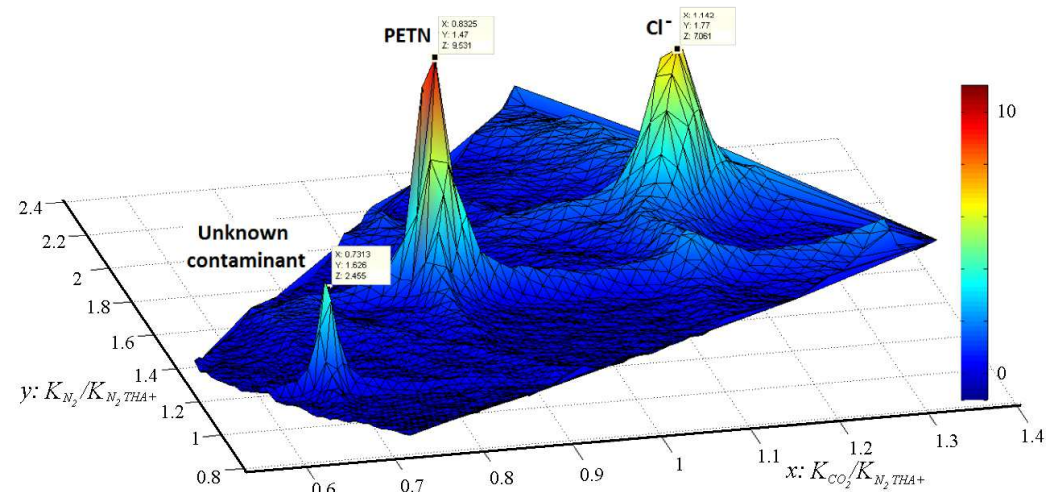
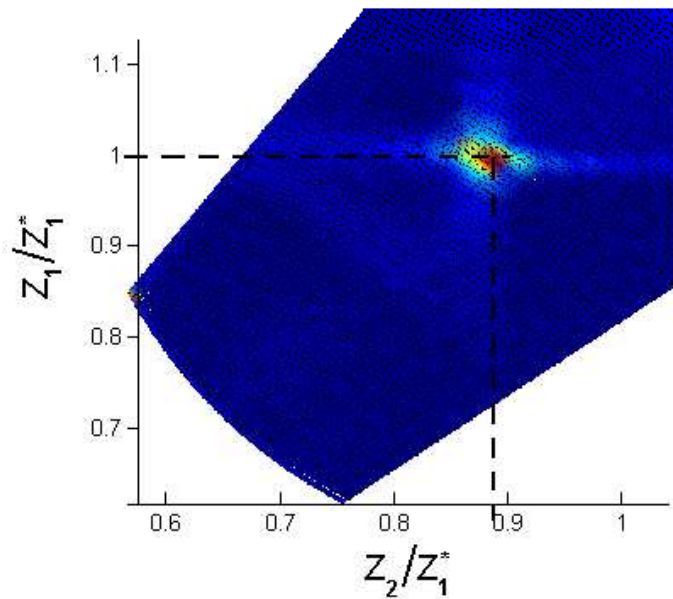


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TMIMS-2: IMS²

- ESI: MeOH, H₂O, THABr.
- Stage 1: N₂
- Stage 2: N₂ with 1% iso-propanol.

- ESI: MeOH, H₂O, HCl, PETN
- Stage 1: CO₂
- Stage 2: N₂



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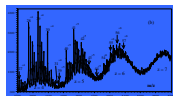
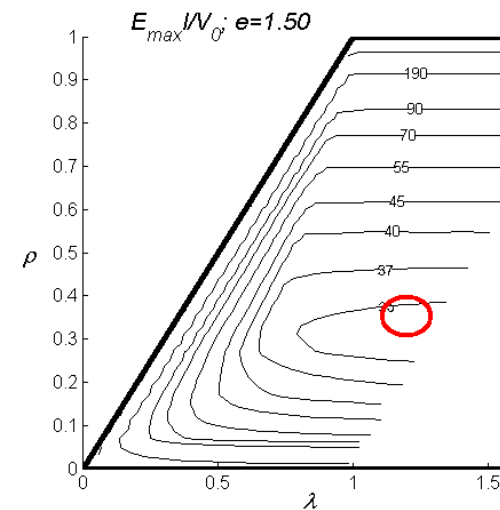
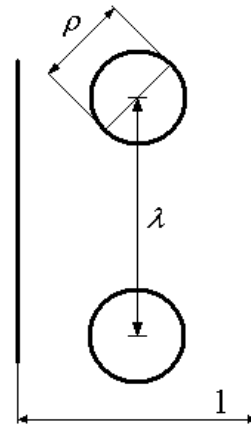
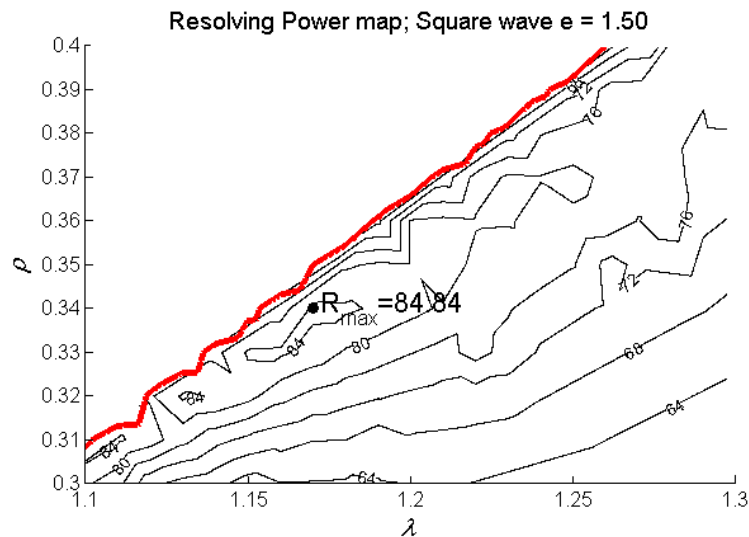
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Numerical simulations:

- Allow us to simulate real geometries.
 - Electric fields: Boundary Element Method.
 - Ideal convective trajectories: Runge-Kutta.
 - Diffusive model: Transversal diffusion $\sigma^2_r = 2D\tau$
- Validated with TMIMS-1 and TMIMS-2.
- Used to determine optimum geometries



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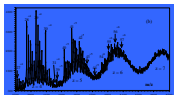
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Conclusions

- Transversal Modulation IMS (TM-IMS) works.
- Resolving power: $R=55$
- Very robust.
- Duty cycle: 100%
- True mobility
- Inlet and outlet are very accessible.
- Allows IMS, IMS² and can be deactivated.
- Operates at atmospheric pressure
 - Upstream the orifice plate.
 - Allows easy upgrading of current API-MS
- Good candidate for IMS-MS applications.



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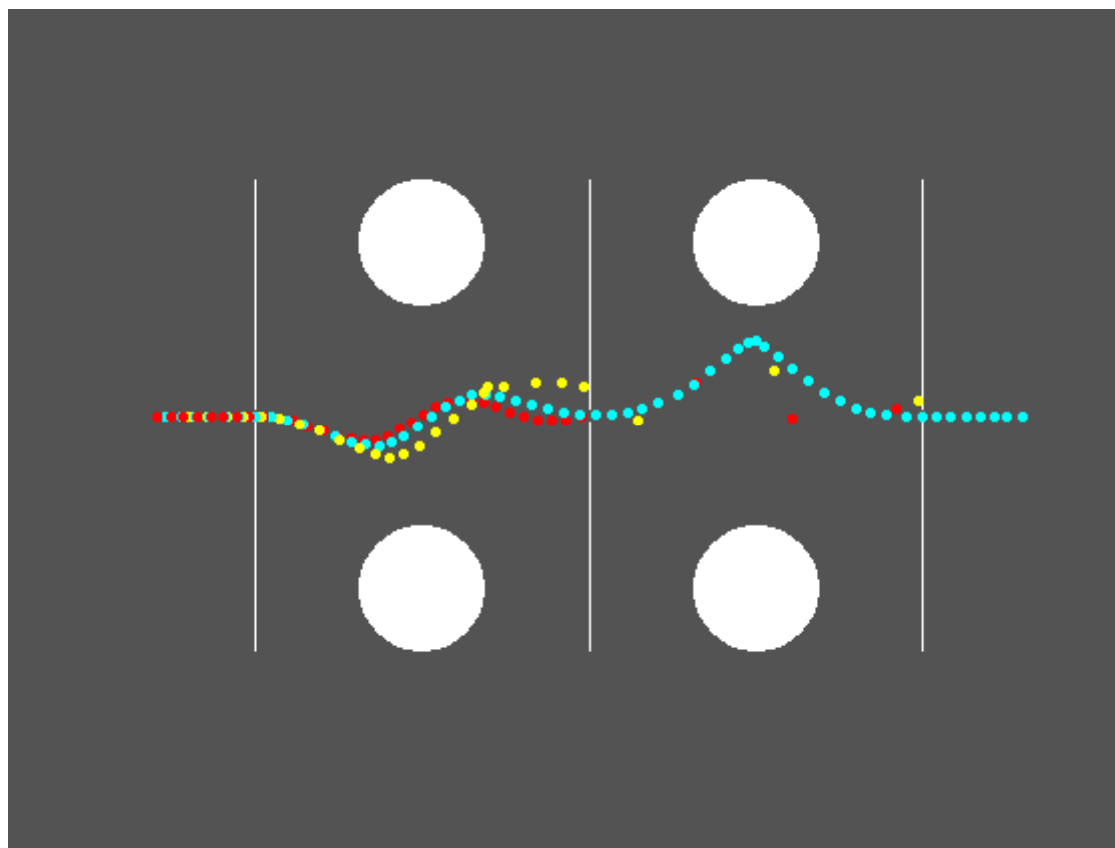


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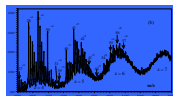


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Thanks for your attention!



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